## **Interview Summary**

The Applicant wishes to thank the Examiner for the telephone interview dated June 19, 2006. In the interview, prior art patent U.S. 6,925,142 and Japanese Publication #61-201182A were discussed. An amendment adding the limitation that the controller device maintains a nonuniform temperature profile along the array was discussed, and the Examiner indicated that such an amendment would overcome the prior art cited.